

<p>Substitute for form 1449/PTO</p> <p>NOV 09 2007</p> <p>U.S. PATENT & TRADEMARK OFFICE</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(Use as many sheets as necessary)</p>				Complete if Known	
				Application No.:	10/549,863
				Filing Date:	December 8, 2006
				First Named Inventor:	Nigel P. Smith
				Art Unit:	2823
				Examiner Name:	William D. Coleman
Sheet	1	of	1	Attorney Docket No.:	NAN154 US 8026

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	13.	IBM Corp. (March 1990). "Interferometric Method of Checking the Overlay Accuracy in Photolitho-Graphic Exposure Processes," <i>IBM Technical Disclosure Bulletin</i> 32(10B):214-217.	
	14.	International Search Report mailed on October 15, 2004 for PCT Application No. PCT/GB2004/001533 filed on April 8, 2004 by AOTI Operating Company, Inc, 4 pages.	
	15.	International Preliminary Report on Patentability and Written Opinion mailed on October 14, 2005 for PCT Application No. PCT/GB2004/001533 filed on April 8, 2004 by AOTI Operating Company, Inc., 7 pages.	
	16.	Smith, Nigel P. et al. (August 1993). "Minimising Optical Overlay Measurement Errors," <i>Integrated Circuit Metrology, Inspection, and Process Control VII. Proceedings of SPIE</i> 1926:450-462.	

Examiner Signature:	Date Considered:	
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* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.